Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/659,974	KRYZAK ET AL.
	Examiner	Art Unit
	Ted M. Wang	2611

SEARCHED

Class	Subclass	Date	Examiner
	UPDATED		
370	535	4/24/2008	TW
455	73, 88	4/24/2008	TW
455	507	4/24/2008	TW
375	219, 220	4/24/2008	TW
375	222	4/24/2008	TW

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
375	**219, 220**	4/24/2008	**TW**
375	222	4/24/2008	TW
370	535	4/24/2008	TW
455/73, 88, 507		4/24/2008	TW

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST - USPGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB, see attached search report	4/24/2008	TW
ODP- searched and reviewed from PALM and EAST.	4/24/2008	TW
Inventor search - (Kryzak with (Joseph or Neil)) or (Hoelscher with Aaron) or (Rock with Thomas)	4/24/2008	TW
IEEE- Author - Kryzak J. and Hoelscher A. and Rock T. and Kryzak J. N.	4/24/2008	TW
IEEExplor - Advance search - Bond* (code or sequence) and transceiver and master and slave and detect and delay	4/24/2008	TW